Amendment under 37 CFR §1.111 Application No. 10/583,660 Attorney Docket No. 062668

**REMARKS** 

(1) Claims 1-6 are pending in this application, of which claims 1-3 have been amended, and

claims 4-6 have been added.

(2) Claims 1-3 were rejected under 35 U.S.C. §102(e) as being anticipated by Matsuyama et

al. (U.S. Patent No. 6,327,379 B2). Item 4 of the outstanding Office Action.

(3) Claim 1 has been amended. The amendment of claim 1 is supported at page 8, lines 15-

19; and page 12, lines 5-14 of the original specification. Note that the "inside area data

generation means" is described at page 8, line 15; the "outside area data generation means" is

described at page 11, lines 21-22; the "inside determination means" is described at page 11, line

11; and the "outside determination means" is described at page 13, line 17.

(4) The Examiner states that Matsuyama et al. disclose all the limitations of the invention

recited in original claims. In particular, the Examiner states that "an inspection data generation

means for generating inspection data in the inside (pattern image fig 4, element 21) and outside

of a pattern area to be inspected (pattern outside is auxiliary pattern, fig 4, element 22)." It

appears that the Examiner considers that element 21 of Matsuyama et al. corresponds to the

"inside area" of a pattern to be inspected, and that element 22 of Matsuyama et al. corresponds to

the "outside area" of the pattern.

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Matsuyama et al. disclose as Field of the Invention that in order to avoid a phenomenon

that the corners of a pattern 11 are round, an auxiliary pattern 12 are formed at a respective

corner of the rectangular pattern 10. See col. 1, lines 17-30. In the inspection taught by

Matsuyama et al., the image of the auxiliary pattern is deleted, and the image obtained from

deleting the auxiliary pattern is inspected. See col. 2, lines 18 to 33. As illustrated in Figs. 4 and

6A, the auxiliary pattern 22 is positioned only at each corner of the pattern image 21. The

auxiliary pattern does not surround the image pattern 21. In addition, the auxiliary pattern 22 of

Matsuyama et al. is removed to inspect the image (col. 2, lines 31-33). In other words, the

auxiliary pattern 22 is an area to be excluded from the inspection in Matsuyama et al.

On the contrary, in amended claim 1, the outside area surrounds the inside area of the

pattern area to be inspected. In amended claim 1, the pattern area can be inspected in such a

manner that the outside area of the pattern area is strictly inspected in order to avoid a short

circuit with the adjacent pads or wiring patterns while the inside area of the pattern area is

inspected under a relaxed inspection standard. As disclosed in Fig. 3, the outside area 22a

surrounds the inside area 21b. As described at page 4, line 24 to page 5, line 6 of the original

specification, a stricter inspection reference can be applied to the outside area than to the inside

area, as recited in newly added claim 4. Therefore, the invention recited in claims 1 or 4 is

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different from Matsuyama et al. Thus, the rejection of the claims under 35 U.S.C. §102(e) is not

supported by Matsuyama et al.

Moreover, amended claim 1 additionally has incorporate the limitations of "the inside

area data generation means performing a reduction processing of the inside area to generate the

first inspection data," and "the outside area data generation means performing an expansion

processing of the outside area to generate the second inspection data." There features are not

disclosed or suggested by the references.

(5) Newly added claim 4 is supported at page 4, line 24 to page 5, line 6 of the original

specification. Newly added claims 5 and 6 are supported at page 12, line 5 to page 13, line 25 of

the original specification. The features recited in these claims are not disclosed by the references.

(6) In view of above, Applicant submits that the claims, as herein amended, are in condition

for allowance. Applicant requests such action at an early date. If the Examiner believes that this

application is not now in condition for allowance, the Examiner is requested to contact

Applicant's undersigned representative at the telephone number indicated below to arrange for an

interview to expedite the disposition of this case.

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If this paper is not timely filed, Applicant respectfully petitions for an appropriate extension of time. The fees for such an extension or any other fees that may be due with respect to this paper may be charged to Deposit Account No. 50-2866.

Respectfully submitted,

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